

Koji Sueoka

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The third column is the impact factor (IF) of the journal, and the fourth column is the number of citations of the article.

89
papers

549
citations

13
h-index

20
g-index

93
ext. papers

608
ext. citations

2.1
avg, IF

3.95
L-index

#	Paper	IF	Citations
89	Density functional theory study on the impact of heavy doping on Si intrinsic point defect properties and implications for single crystal growth from a melt. <i>Journal of Applied Physics</i> , 2013 , 114, 153510	2.5	43
88	Ab initio study of vacancy and self-interstitial properties near single crystal silicon surfaces. <i>Journal of Applied Physics</i> , 2012 , 111, 083507	2.5	32
87	A study on density functional theory of the effect of pressure on the formation and migration enthalpies of intrinsic point defects in growing single crystal Si. <i>Journal of Applied Physics</i> , 2012 , 111, 093529	2.5	24
86	Theoretical study of the impact of stress on the behavior of intrinsic point defects in large-diameter defect-free Si crystals. <i>Journal of Crystal Growth</i> , 2013 , 363, 97-104	1.6	23
85	Defect Formation Behaviors in Heavily Doped Czochralski Silicon. <i>ECS Transactions</i> , 2006 , 2, 95-107	1	22
84	Silicon Single Crystal Growth from a Melt: On the Impact of Dopants on the V/G Criterion. <i>ECS Journal of Solid State Science and Technology</i> , 2013 , 2, P166-P179	2	20
83	Density functional theory calculations for estimation of gettering sites of C, H, intrinsic point defects and related complexes in Si wafers. <i>Materials Science in Semiconductor Processing</i> , 2016 , 44, 13-17	4.3	19
82	Formation Energy of Intrinsic Point Defects in Si and Ge and Implications for Ge Crystal Growth. <i>ECS Journal of Solid State Science and Technology</i> , 2013 , 2, P104-P109	2	19
81	Internal Gettering for Ni Contamination in Czochralski Silicon Wafers. <i>Journal of the Electrochemical Society</i> , 2000 , 147, 3074	3.9	18
80	First principles analysis of atomic configurations of group IV elements in Ge crystal for solar cells. <i>Physica Status Solidi C: Current Topics in Solid State Physics</i> , 2014 , 11, 1718-1721		16
79	Useful Database of Effective Gettering Sites for Metal Impurities in Si Wafers with First Principles Calculation. <i>ECS Journal of Solid State Science and Technology</i> , 2015 , 4, P351-P355	2	14
78	Growth Process of Polyhedral Oxide Precipitates in Czochralski Silicon Crystals Annealed at 1100°C. <i>Japanese Journal of Applied Physics</i> , 1994 , 33, L1507-L1510	1.4	14
77	Review Properties of Intrinsic Point Defects in Si and Ge Assessed by Density Functional Theory. <i>ECS Journal of Solid State Science and Technology</i> , 2016 , 5, P3176-P3195	2	13
76	Stress and doping impact on intrinsic point defect behavior in growing single crystal silicon. <i>Physica Status Solidi (B): Basic Research</i> , 2014 , 251, 2159-2168	1.3	12
75	Calculation of Size Distribution of Void Defects in CZ Silicon. <i>Journal of the Electrochemical Society</i> , 2003 , 150, G587	3.9	12
74	Analysis of Local Lattice Strain Around Oxygen Precipitates in Czochralski-Grown Silicon Wafers Using Convergent Beam Electron Diffraction. <i>Japanese Journal of Applied Physics</i> , 1999 , 38, 3440-3447	1.4	11
73	The Hakoniwa method, an approach to predict material properties based on statistical thermodynamics and ab initio calculations. <i>Materials Science in Semiconductor Processing</i> , 2016 , 43, 209-213	4.3	10

72	On intrinsic point defect cluster formation during Czochralski crystal growth. <i>Physica Status Solidi C: Current Topics in Solid State Physics</i> , 2009 , 6, 1906-1911		9
71	Surface-induced charge at a Ge (100) dimer surface and its interaction with vacancies and self-interstitials. <i>Journal of Applied Physics</i> , 2013 , 113, 093503	2.5	8
70	Computer Simulation of Concentration Distribution of Intrinsic Point Defect Valid for All Pulling Conditions in Large-Diameter Czochralski Si Crystal Growth. <i>ECS Journal of Solid State Science and Technology</i> , 2019 , 8, P228-P238	2	7
69	Ab initio analysis of a vacancy and a self-interstitial near single crystal silicon surfaces: Implications for intrinsic point defect incorporation during crystal growth from a melt. <i>Physica Status Solidi (A) Applications and Materials Science</i> , 2012 , 209, 1880-1883	1.6	7
68	First principles analysis on interaction between vacancy near surface and dimer structure of silicon crystal. <i>Journal of Applied Physics</i> , 2012 , 111, 013521	2.5	7
67	Recent Approach to Evaluation of Adhesion of Plated Films. <i>Hyomen Gijutsu/Journal of the Surface Finishing Society of Japan</i> , 2007 , 58, 280-280	0.1	7
66	Control of grown-in defects and oxygen precipitates in silicon wafers with DZ-IG structure by ultrahigh-temperature rapid thermal oxidation. <i>Journal of Applied Physics</i> , 2018 , 123, 161591	2.5	6
65	First Principles Calculation for Cu Gettering by Dopant-Dopant-Vacancy Complex in Silicon Crystal. <i>ECS Transactions</i> , 2006 , 2, 261-273	1	6
64	Impact of Anisotropic Thermal Stress on Behavior of Grown-In Defects during Si Crystal Growth from a Melt. <i>ECS Journal of Solid State Science and Technology</i> , 2016 , 5, P553-P555	2	5
63	Energy band structures of group IV compound semiconductors for solar cells. <i>Physica Status Solidi (B): Basic Research</i> , 2014 , 251, 2221-2224	1.3	5
62	Effect of dangling bonds of ultra-thin silicon film surface on electronic states of internal atoms. <i>Applied Surface Science</i> , 2012 , 258, 5265-5269	6.7	5
61	Impact of the Formation of Dimer Structures at the Surface on the Internal Atoms of Si Thin Film. <i>Journal of the Electrochemical Society</i> , 2010 , 157, H323	3.9	5
60	First-Principles Calculation on the Stable Structure and Adhesive Strength of Ni/Fe(100) or Cu/Fe(100) Interfaces. <i>Nippon Kinzoku Gakkaishi/Journal of the Japan Institute of Metals</i> , 2007 , 71, 1024-1031	0.4	5
59	Theoretical Study of Impact of Internal and External Stresses on Thermal Equilibrium Concentrations of Intrinsic Point Defects in Doped Si Crystals. <i>ECS Journal of Solid State Science and Technology</i> , 2017 , 6, P78-P99	2	4
58	Density Functional Theory Study on Formation Energy and Diffusion Path of Metal Atom near Dopant in Si Crystals. <i>ECS Journal of Solid State Science and Technology</i> , 2017 , 6, P125-P131	2	4
57	An atomistic picture of the diffusion of two vacancies forming a di-vacancy in Si. <i>Physica Status Solidi (B): Basic Research</i> , 2014 , 251, 2185-2188	1.3	4
56	A Statistical Model Describing Temperature Dependent Gettering of Cu in p-Type Si. <i>ECS Journal of Solid State Science and Technology</i> , 2015 , 4, P232-P235	2	4
55	Simulation of STM Images on a Flat Si (110)-(8 \times 8) Surface Using Density Functional Theory. <i>Journal of the Electrochemical Society</i> , 2012 , 159, H201-H207	3.9	4

54	First-principles study on initial stage of oxidation on Si(110) surface. <i>Physica Status Solidi C: Current Topics in Solid State Physics</i> , 2011 , 8, 717-720		4
53	Gettering Sinks for Metallic Impurities Formed by Carbon-Cluster Ion Implantation in Epitaxial Silicon Wafers for CMOS Image Sensor. <i>IEEE Journal of the Electron Devices Society</i> , 2018 , 6, 1200-1206	2.3	4
52	Density functional theory study of stable configurations of substitutional and interstitial C and Sn atoms in Si and Ge crystals. <i>Journal of Crystal Growth</i> , 2017 , 463, 110-115	1.6	3
51	Estimation of the temperature dependent interaction between uncharged point defects in Si. <i>AIP Advances</i> , 2015 , 5, 017127	1.5	3
50	Stability of Excess Oxygen Atoms near Oxide Precipitate and Oxygen Solubility in Silicon Crystal. <i>ECS Journal of Solid State Science and Technology</i> , 2018 , 7, P102-P108	2	3
49	DFT study of the effect of hydrostatic pressure on formation and migration enthalpies of intrinsic point defects in single crystal Si. <i>Physica Status Solidi C: Current Topics in Solid State Physics</i> , 2012 , 9, 1947-1951 ³		
48	First Principles Calculation of the Mechanism of Oxygen Precipitation in Czochralski Silicon Crystals (Effects of Heavy Boron Doping). <i>Journal of Solid Mechanics and Materials Engineering</i> , 2007 , 1, 1165-1174		3
47	Oxygen Precipitation Behaviour and Internal Gettering in Epitaxial and Polished Czochralski Silicon Wafers. <i>Solid State Phenomena</i> , 1999 , 69-70, 63-72	0.4	3
46	Numerical analysis of effect of thermal stress depending on pulling rate on behavior of intrinsic point defects in large-diameter Si crystal grown by Czochralski method. <i>Journal of Crystal Growth</i> , 2020 , 531, 125334	1.6	3
45	First-principles calculation of atomic configurations of carbon and tin near the surface of a silicon thin film used for solar cells. <i>Materials Science in Semiconductor Processing</i> , 2017 , 63, 45-51	4.3	2
44	Theoretical study on Frenkel pair formation and recombination in single crystal silicon. <i>Journal of Crystal Growth</i> , 2019 , 520, 1-10	1.6	2
43	Struggle between inner atoms of ultra-thin silicon film and both its dimer surfaces. <i>Results in Physics</i> , 2012 , 2, 185-189	3.7	2
42	Molecular simulation on interfacial structure and gettering efficiency of direct silicon bonded (110)/(100) substrates. <i>Journal of Applied Physics</i> , 2010 , 107, 113509	2.5	2
41	Density Functional Theory Study on Stability of Fe, Cu, and Ni Atoms Near (001) Surface of Si Wafer. <i>ECS Journal of Solid State Science and Technology</i> , 2019 , 8, P573-P579	2	2
40	Density Functional Theory Calculations of Atomic Configurations and Bandgaps of C-, Ge-, and Sn-Doped Si Crystals for Solar Cells. <i>ECS Journal of Solid State Science and Technology</i> , 2017 , 6, P326-P331 [†]		1
39	Impacts of thermal stress and doping on intrinsic point defect properties and clustering during single crystal silicon and germanium growth from a melt. <i>Journal of Crystal Growth</i> , 2017 , 474, 96-103	1.6	1
38	Systematic Density Functional Theory Investigation of Stability of Dopant Atoms in Ge Ultra-Thin Film Grown on Si Substrate. <i>ECS Journal of Solid State Science and Technology</i> , 2017 , 6, P154-P160	2	1
37	Prediction of O Aggregation in Straight Line at High Temperature in Si Crystals: Thermal Donors Attaching to an Oxide Precipitate Surface. <i>ECS Journal of Solid State Science and Technology</i> , 2020 , 9, 054003	2	1

36	Effect of Oxygen Precipitation in Silicon Wafer on Electrical Characteristics of Fully Ion-Implanted n-Type PERT Solar Cells. <i>ECS Journal of Solid State Science and Technology</i> , 2019 , 8, P596-P601	2	1
35	Formation energy of intrinsic point defects in nanometer-thick Si and Ge foils and implications for Ge crystal growth from a melt. <i>Physica Status Solidi C: Current Topics in Solid State Physics</i> , 2014 , 11, 85-88		1
34	Intrinsic point defect behavior close to silicon melt/solid interface 2015 ,		1
33	Atom probe tomography study on Ge _{1-x} Sn _x Cy hetero-epitaxial film on Ge substrates. <i>Thin Solid Films</i> , 2015 , 592, 54-58	2.2	1
32	First-Principles Calculation on Initial Stage of Oxidation of Si (110)-(1 × 1) Surface. <i>Advances in Condensed Matter Physics</i> , 2011 , 2011, 1-5	1	1
31	A Comparison of Intrinsic Point Defect Properties in Si and Ge. <i>Materials Research Society Symposia Proceedings</i> , 2008 , 1070, 1		1
30	Ab Initio Analysis of Point Defects in Plane-Stressed Si Single Crystal. <i>Journal of Computational Science and Technology</i> , 2008 , 2, 478-487		1
29	Ab Initio Analysis on Stability of Carbon-Hydrogen Complex in Si Crystal under Compressive Stress along [110] Direction. <i>Nihon Kikai Gakkai Ronbunshu, A Hen/Transactions of the Japan Society of Mechanical Engineers, Part A</i> , 2006 , 72, 1200-1206		1
28	First Principle Calculations on Interaction between Cu Atom and Dopants in Silicon Crystal. <i>Nihon Kikai Gakkai Ronbunshu, A Hen/Transactions of the Japan Society of Mechanical Engineers, Part A</i> , 2005 , 71, 1103-1108		1
27	Preferential Growth Mode of Large-Sized Vacancy Clusters in Silicon: A Neural-Network Potential and First-Principles Study. <i>Journal of Physical Chemistry C</i> ,	3.8	1
26	A statistical model for the gettering of impurities on an atomistic scale. <i>Physica Status Solidi C: Current Topics in Solid State Physics</i> , 2016 , 13, 746-749		1
25	Theoretical study of hydrogen impact on concentration of intrinsic point defects during Czochralski Si crystal growth. <i>Journal of Crystal Growth</i> , 2021 , 555, 125971	1.6	1
24	Differential clustering of self-interstitials during Si crystal growth. <i>Journal of Crystal Growth</i> , 2021 , 574, 126313	1.6	1
23	Novel Description of Oxidizing Reactions in SiO ₂ /Si (100) Interface and Framework for Estimating Interface State Density. <i>ECS Journal of Solid State Science and Technology</i> , 2020 , 9, 024013	2	0
22	Unsteady numerical simulations considering effects of thermal stress and heavy doping on the behavior of intrinsic point defects in large-diameter Si crystal growing by Czochralski method. <i>Journal of Crystal Growth</i> , 2020 , 532, 125433	1.6	0
21	Density functional theory study on concentration of intrinsic point defects in growing N-doped Czochralski Si crystal. <i>Journal of Crystal Growth</i> , 2021 , 571, 126249	1.6	0
20	Atomic structures and stability of finite-size extended interstitial defects in silicon: Large-scale molecular simulations with a neural-network potential. <i>Scripta Materialia</i> , 2022 , 214, 114650	5.6	0
19	A Prediction for Adhesion Forces Between Resin/metal Interfaces Through the First Principles Calculation. <i>Journal of the Adhesion Society of Japan</i> , 2016 , 52, 287-292	0.1	

- 18 First principles analysis on the stability of C, Sn atoms near the surface of Ge thin film. *Transactions of the JSME (in Japanese)*, **2018**, 84, 17-00542-17-00542 0.2
- 17 Theoretical Study of the Impact of Substitutional Dopants and Thermal Stress on the Behavior of Intrinsic Point Defects in Growing Single Crystal Silicon. *Hyomen Kagaku*, **2016**, 37, 116-121
- 16 Comment on Investigations of interstitial generations near growth interface depending on crystal pulling rates during CZ silicon growth by detaching from the melt [by T. Abe et al. [J. Cryst. Growth 434 (2016) 128-137] and on Observations of secondary defects and vacancies in CZ silicon crystals detached from melt using four different types of characterization techniques by T. Abe et al. [J. Cryst. Growth 436 (2016) 313-315]. *Journal of Crystal Growth*, **2018**, 449, 163-175 1.6
- 15 Density Functional Theory Study of the Stress Impact on Formation Enthalpy of Intrinsic Point Defect around Dopant Atom in Ge Crystal. *ECS Journal of Solid State Science and Technology*, **2017**, 6, P383-P398 2
- 14 Theoretical Study of the Impact of Stress on the Behavior of Intrinsic Point Defects in Large-Diameter Defect-Free Si Crystals. *Solid State Phenomena*, **2013**, 205-206, 163-168 0.4
- 13 First-principles calculation on screw defects at Si(110)/(100) interface. *Physica Status Solidi C: Current Topics in Solid State Physics*, **2011**, 8, 690-693
- 12 First Principles Analysis of Ultra-Thin Silicon Films with Dimer Structures. *Materials Research Society Symposia Proceedings*, **2011**, 1370, 89
- 11 First Principles Analysis of Formation Energy of Point Defects and Voids in Silicon Crystals during the Cooling Process of Czochralski Method (Dopant Type and Concentration Dependence). *Journal of Solid Mechanics and Materials Engineering*, **2007**, 1, 1175-1185
- 10 First Principles Calculation on Oxygen Precipitation Mechanism in Si Crystals (Effect of Heavy B-Doping on Oxygen Precipitation). *Nihon Kikai Gakkai Ronbunshu, A Hen/Transactions of the Japan Society of Mechanical Engineers, Part A*, **2006**, 72, 369-376
- 9 First Principles Analysis on Formation Energy of Point Defects and Voids in Si Crystals during Cooling Process of Czochralski Method (Dopant Type and Concentration Dependence). *Nihon Kikai Gakkai Ronbunshu, A Hen/Transactions of the Japan Society of Mechanical Engineers, Part A*, **2006**, 72, 801-808
- 8 125 First principles analysis on proximity gettering sites formed by C₃H₅ cluster ion implantations. *The Proceedings of the Computational Mechanics Conference*, **2015**, 2015.28, _125-1_-_125-2_ 0.2
- 7 037 First Principles Analysis on Stability of Polyethylene on Metal Surface. *The Proceedings of the Computational Mechanics Conference*, **2015**, 2015.28, _037-1_-_037-3_ 0
- 6 First principles calculation on distribution of vacancy near Si(100) surface area. *The Proceedings of the Computational Mechanics Conference*, **2016**, 2016.29, 4_100 0
- 5 Impurity Gettering used by Hakoniwa method in Si crystals. *The Proceedings of the Computational Mechanics Conference*, **2017**, 2017.30, 091 0
- 4 1407 First-Principles Calculation on Stable Site of Metal Impurities in Si and Ge crystals. *The Proceedings of the Computational Mechanics Conference*, **2011**, 2011.24, 467-468 0
- 3 1404 First Principles Analysis on Band Gap of Si Quantum Dots for Solar Cells. *The Proceedings of the Computational Mechanics Conference*, **2011**, 2011.24, 460-462 0
- 2 Effective gettering sites for metal impurities in Si wafers searched by first principles calculation. *The Proceedings of the Computational Mechanics Conference*, **2014**, 2014.27, 134-136 0
- 1 Theoretical study of stress impact on formation enthalpy and thermal equilibrium concentration of impurities and dopants in Si single crystal. *Journal of Crystal Growth*, **2021**, 572, 126284 1.6

